

<b>STN</b>	<b>Polovodičové zariadenia</b> <b>Polovodičové zariadenia pre systém IoT</b> <b>Časť 1: Skúšobná metóda detekcie kolísania</b> <b>zvuku</b>	<b>STN</b> <b>EN IEC 63364-1</b>  35 8793
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Semiconductor devices - Semiconductor devices for IoT system - Part 1: Test method of sound variation detection

Táto norma obsahuje anglickú verziu európskej normy.  
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 03/23

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**EN IEC 63364-1**

January 2023

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English Version

**Semiconductor devices - Semiconductor devices for IoT system  
- Part 1: Test method of sound variation detection  
(IEC 63364-1:2022)**

Dispositifs à semiconducteurs - Dispositifs à  
semiconducteurs pour système IDO - Partie 1: Méthode  
d'essai de détection de variation acoustique  
(IEC 63364-1:2022)

Halbleiterbauelemente - Halbleiterbauelemente für IOT-  
Systeme - Teil 1: Prüfverfahren für die Erkennung von  
Schallschwankungen  
(IEC 63364-1:2022)

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**EN IEC 63364-1:2023 (E)****European foreword**

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**IEC 63364-1**

Edition 1.0 2022-12

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

**Semiconductor devices – Semiconductor devices for IoT system –  
Part 1: Test method of sound variation detection**

**Dispositifs à semiconducteurs – Dispositifs à semiconducteurs pour système  
IDO –  
Partie 1: Méthode d'essai de détection de variation acoustique**



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# IEC 63364-1

Edition 1.0 2022-12

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

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**Semiconductor devices – Semiconductor devices for IoT system –  
Part 1: Test method of sound variation detection**

**Dispositifs à semiconducteurs – Dispositifs à semiconducteurs pour système  
IDO –  
Partie 1: Méthode d’essai de détection de variation acoustique**

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SEMICONDUCTOR DEVICES –  
SEMICONDUCTOR DEVICES FOR IOT SYSTEM –

**Part 1: Test method of sound variation detection**

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Draft	Report on voting
47/2782/FDIS	47/2792/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at [www.iec.ch/members\\_experts/refdocs](http://www.iec.ch/members_experts/refdocs). The main document types developed by IEC are described in greater detail at [www.iec.ch/publications](http://www.iec.ch/publications).

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## **SEMICONDUCTOR DEVICES – SEMICONDUCTOR DEVICES FOR IOT SYSTEM –**

### **Part 1: Test method of sound variation detection**

#### **1 Scope**

This part of IEC 63364 specifies terms, the test method, and the report of sound variation detection system based on IoT. It provides the evaluation method for each part of the sound variation detection system based on IoT in the block diagram, the characterization parameters, symbols, test setups and the conditions. In addition, this document defines the configuration items and criteria of standard space and firing situation for the quality evaluation measurement of sound field variation detection system with IoT.

#### **2 Normative references**

There are no normative references in this document.

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